

last detailed report on electronic performance in May tracker week <u>http://www.hep.ph.ic.ac.uk/~dmray/CBC_documentation/CBC_Tracker_Electronics_May_11.pdf</u>

will not repeat details here, but briefly summarize

since then most of effort on tests with sensors lab with beta source recent test beam

progress on definition of next chip iteration for 2S-Pt modules

Tracker Phase 2 Upgrade Electronics, Oct. 2011. Mark Raymond, Imperial College

CBC overview

2.5 -> 1.25 DC-DC converter

features

- designed for short strips, ~2.5–5cm, < ~ 10 pF
- full size prototype 128 channels
 50 μm pitch wirebond
- binary un-sparsified readout
- powering test features
 2.5 -> 1.2 DC-DC converter
 LDO regulator (1.2 -> 1.1) feeds analog FE

main functional blocks

- fast front end amplifier 20 nsec peaking
- comparator with programmable threshold trim
- 256 deep pipeline (6.4 us)
- 32 deep buffer for triggered events
- fast (SLVS) and slow (I2C) control interfaces

front end

- DC coupling to sensor up to 1 uA leakage
- · can be used for both sensor polarities



CBC under test

produced in IBM 130 nm CMOS process

2010 CERN MPW run

chips on test bench since Feb. 2011

fully functioning chip

a few workarounds needed for biasing issues (see previous talk)



2 consecutive data frames (2 triggers)







preamp: leakage tolerance 1µA verified, both polarities

postamp: gain: ~ 50 mV / fC





comparator

thresholds

before tuning pk-pk threshold spread ~30 mV (~ 0.6 fC)

tuning reduces spread to ~ mV level

timewalk

timewalk spec. < 16 ns between 1.25 and 10 fC signals, with comp. threshold set to 1 fC measurements just within spec.

timewalk: threshold at 1 fC





noise and power

measurement technique

vary current in input transistor to keep pulse shape independent of C

=> analogue power consumption depends on C

close agreement between measurements (solid symbols) & simulations (open circles)

results

noise (rms electrons): ~ 500 + 64 / pF analogue power: 130 + 21 / pF μ W / channel



e.g. ~ 800e noise for analog power ~ 250 μ W/chan for 5 pF input capacitance

no significant difference between electrons and holes modes

overall power

digital: $I_{VDDD} = 2.8 - 4.5$ mA for whole chip (depends on SLVS bias setting) < 50 μ W / channel

total:

180 + (21 x C_{SENSOR}[pF]) μ W / channel

e.g. < 300 uW /channel for 5 pF sensor capacitance

power features

DC-DC switched capacitor converter

converts 2.5 -> ~ 1.2

clearly functioning

effect of switch noise needs careful study

LDO linear regulator

provides clean, regulated rail to analog FE

~ 1.2 Vin, 1.1 Vout

dropout ~ 40 mV for 60 mA load

provides > 30dB supply rejection up to 10 MHz

(see May talk for more detail)

DC-DC & LDO outputs





results with sensors

preparations for (and tests with) sensors have dominated activities in recent months

CBC module



interface card for level shift and power supply

all signals LVDS I2C at 5 / 3.3V levels

+/- 5V & sensor bias

lab system for source measurements



need TDC to timestamp scintillator trigger

can then select appropriately timed signals by TDC value

beta source results

method

choose comparator threshold (programmable) count number of clusters in CBC output signal for fixed number of scintillator triggers repeat for range of comparator thresholds

plot no. of clusters vs. comparator threshold -----

shape depends on signal arrival time (TDC value)

need to select events by TDC value so that triggered timeslice contains all signal sizes (T_{OPT})

if select signals occurring too early/late then get spectrum where some signals fire comparator in previous/subsequent timeslice

(see backup slides for more detailed explanation of histogram shapes)



beta source - landau fitting

can fit raw data with curve generated from Landau distribution 1000

compare most prob. signal size with electronic test charge injection

-> most prob. signal value ~3.7 fC (23,000 e)

840 electrons noise





Sr-90 source



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test beam

CBC module operated parasitically in UA9 crystal collimation test beam - September, 2011

H8 beam line, 400 GeV protons

UA9 telescope implemented using CMS tracker readout

D0 sensors + APV analog optical link CMS FED,... CMS DAQ software

for further details see: M Pesaresi *et al* 2011 *JINST* **6** P04006





CBC module location



XY plane 5

CBC module follows final telescope plane

no time for elegant solutions

long distance digital signal transmission (clock, trigger, data) implemented using commercial optical components



control and DAQ signal sequencing implemented in APVE FPGA board (also TDC functionality) allows to delay & synchronize CBC data with APV - so FED sees CBC data as if from an APV quite complicated thing to do but simplifies things from DAQ point of view

=> FED & DAQ can process CBC data as if from an APV (including zero suppression) CBC data injected electrically into FED front end after optical receiver (before ADC) 13



test beam - first results



plots provided by Will Ferguson (IC)



"hi-tech" 2-in-1 module concept proposed for outer tracker layers bring signals from 2 strip (SS) sensor layers together in one chip look for cluster correlations to identify high Pt stub

plan to prototype logic to implement correlation in next CBC version allows to study issues involved with constructing such a module

=> 256 channel bump-bondable chip required

next CBC version

design has begun 250 µm pitch C4 pads

some issues to confront:

chip and hybrid design has to proceed in parallel - routing capabilities of substrate has impact on pad locations (hybrid design - Georges Blanchot)

how to test? - prototype and production

wafers for eventual bump-bond have to be kept in ultra-clean environment

but need to identify good chips for good multi-chip module yield

=> wafer probing, but probably not possible in home labs

verify single chip performance on dedicated substrate - yield not important here



next version

256 channels bump-bond: 250 um pitch 11.4mm x 4.75mm

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layout by Davide Braga (RAL) 17

triggering logic





3 new blocks required

cluster width discrimination

simple logic to exclude wide clusters

correlation & offset correction

relatively simple logic to correct for phi offset across module and perform correlation trigger data formation and off-chip transmission

foreseen to be just simple OR for this chip version

=> 1 bit to signify high PT stub detected (no Pt stub address)

eventual requirements here still under consideration

synchronous or asynchronous options are possible

summary

CBC testing status

tests with sensors have dominated activities in recent months beta source measurements show results consistent with performance measured electronically

lab measurements also confirmed in test beam further analysis of test beam data underway

further chip testing

more detailed study of powering options temperature effects (work underway at Bristol - David Cussans) radiation: ionizing and SEU



next chip iteration

plan to submit 256 channel bump-bondable version with triggering features, early 2012

extra slides

comp. threshold scan explanation - early events



comp. threshold scan explanation - late events





comparator threshold [mV] 2.3

CWD logic



n-1, n, n+1, ... are neighbouring channels on sensor layer (inner or outer) but every other channel on chip could increase to accept wider clusters if necessary





* http://indico.cern.ch/getFile.py/access?contribId=3&sessionId=0&resId=0&materiaIId=0&confId=36580

W.E. / R.H.